

T541X107K030CH8610

T541 HRA, Tantalum, Polymer Tantalum, HRA Multi-Anode, 100 uF, 10%, 30 VDC, SMD, Polymer, Molded, High Reliability, Multi-Anode, Low ESR, C (0.01%/1000 Hrs), 70 mOhms, 7343, 4.3 mm, 1.3 mm



General Information	
Series	T541HRA
Dielectric	Polymer Tantalum
Style	SMD Chip
Description	SMD, Polymer, Molded, High Reliability, Multi-Anode, Low ESR
Features	Non-Combustible, Multiple Anode, Low ESR, High Reliability
RoHS	No
Prop 65	WARNING: Cancer and reproductive harm - https://www.p65warnings.ca.gov /
SCIP Number	b064b03e-bd75-42af-b342-1fe 94dec2340
Termination	Tin Lead (SnPb)
AEC-Q200	No
Typical Component Weight	410.89 mg
Shelf Life	52 Weeks
MSL	3

Dimensions	
L	7.3mm +/-0.3mm
W	4.3mm +/-0.3mm
Н	4mm +/-0.3mm
Т	0.13mm REF
S	1.3mm +/-0.3mm
F	2.4mm +/-0.1mm
A	3.8mm MIN
В	0.5mm +/-0.15mm
Е	3.5mm REF
G	3.5mm REF
Р	1.7mm REF
R	1mm REF
Х	0.1mm +/-0.1mm REF

Specifications	
Capacitance	100 uF
Tolerance	10%
Voltage DC	30 VDC (105C), 20.1 VDC (125C)
Temperature Range	-55/+125°C
Rated Temperature	105°C
Life	2000 Hrs (125C)
Humidity	85C, 85% RH, 1000 Hours, rated voltage
Dissipation Factor	10% 120Hz 25C
Failure Rate	C (0.01%/1000 Hrs)
ESR	70 mOhms (100kHz 25C)
Ripple Current	1878 mA (rms, 100kHz 45C)
Leakage Current	300 uA (5min 25°C)
Testing and Reliability	10 Cycles At 25C +/-5C & Improved Humidity Capability

Packaging Specifications	
Packaging	T&R, 178mm
Packaging Quantity	500

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